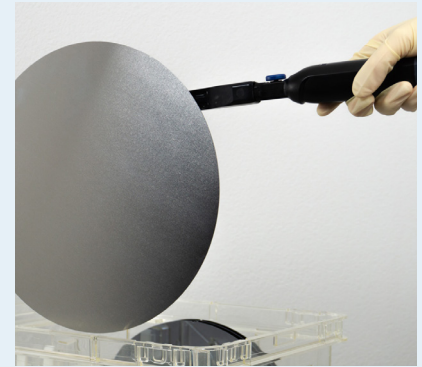


ALUMINUM TEST WAFER

The WHS-W series is a high-quality, bare aluminum test wafer designed for a wide range of cleanroom applications. Available in 100 mm, 150 mm, 200 mm, and 300 mm diameters, these wafers feature either a SEMI-standard notch or flat, making them ideal for operator training, automation setup, target wafer customization, and use as protective electrostatic chuck (PEC) covers during chamber cleaning.

Manufactured from heat-treated aluminum alloy 5754-H22, the WHS-W wafers are engineered to resist deformation and warping under repeated use. With a thickness of 0.8 mm and a surface roughness of 1.6 μm Ra, these bare aluminum wafers come without any surface finish or anodization. This allows customers to modify or customize the wafers as needed for specialized applications, such as target or carrier wafer development.



The WHS-W wafers are especially valuable for robot and wafer handling training, providing a safe and durable alternative to fragile silicon dummy wafers. They are also ideal for automation teaching, enabling engineers to refine robotic movements and processes. In addition, the wafers can serve as PEC covers, protecting sensitive chucks during tool chamber cleaning.

Manufactured in an ISO9001 certified facility and CE certified, the WHS-W series offers a robust, customizable solution for semiconductor manufacturing environments where durability and flexibility are essential.

FEATURES AND ADVANTAGES

- Available in 100 mm, 150 mm, 200 mm, 300 mm
- Bare aluminum, no finish for custom modifications
- SEMI-standard notch or flat configuration
- Heat-treated for warp resistance
- Ideal for training, automation, and PEC protection

ALUMINUM TEST WAFER

ITEM	SPECIFICATIONS
Sizes	100, 150-notch, 150-flat, 200, 300mm
Material, wafer	5754-H22 aluminum
Thickness	0.8 mm
Surface roughness	1.6µm Ra
Finish, prep	Chem-cleaned surface
Cleanliness	ISO 3 (Class 1 FS209E)

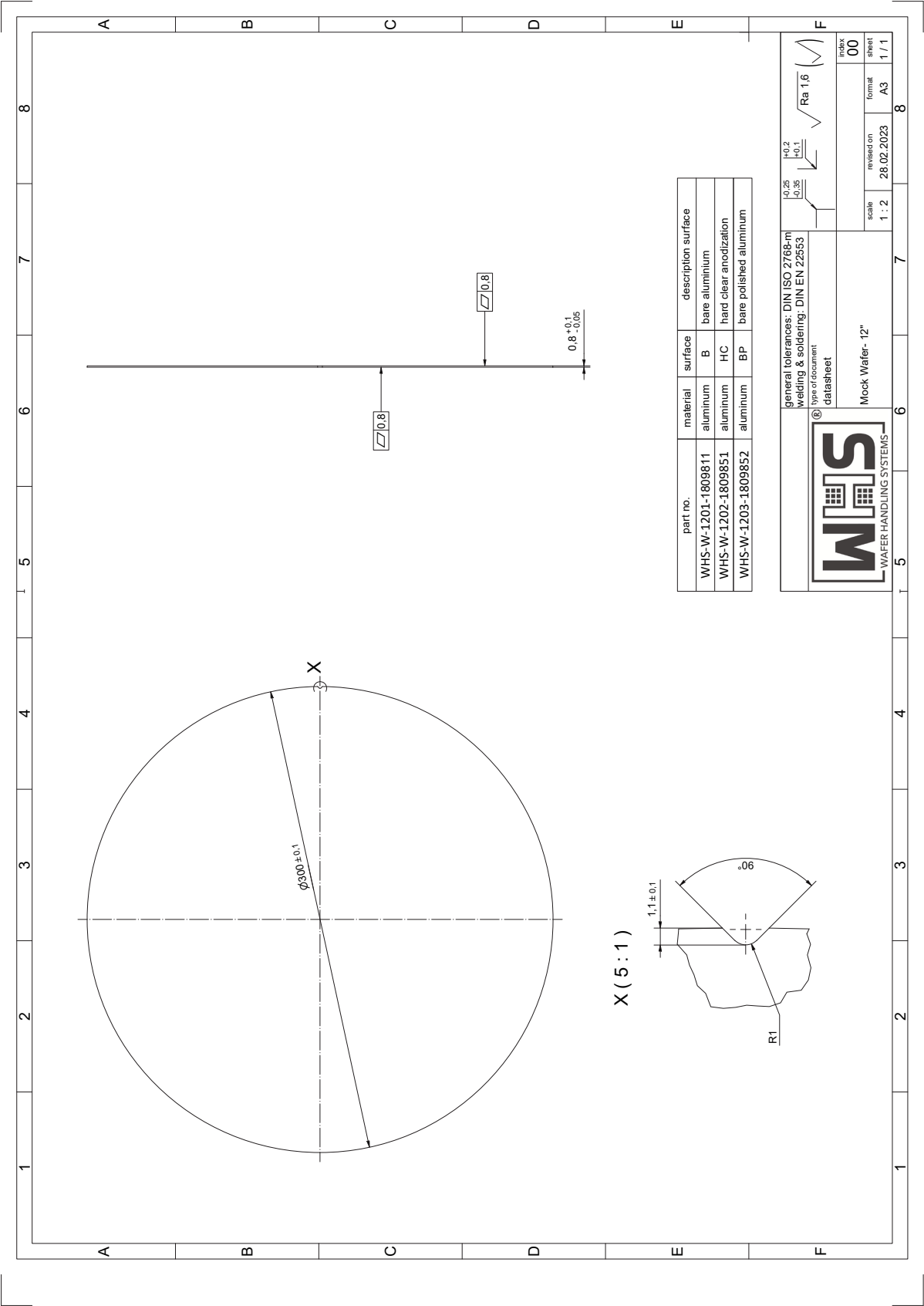


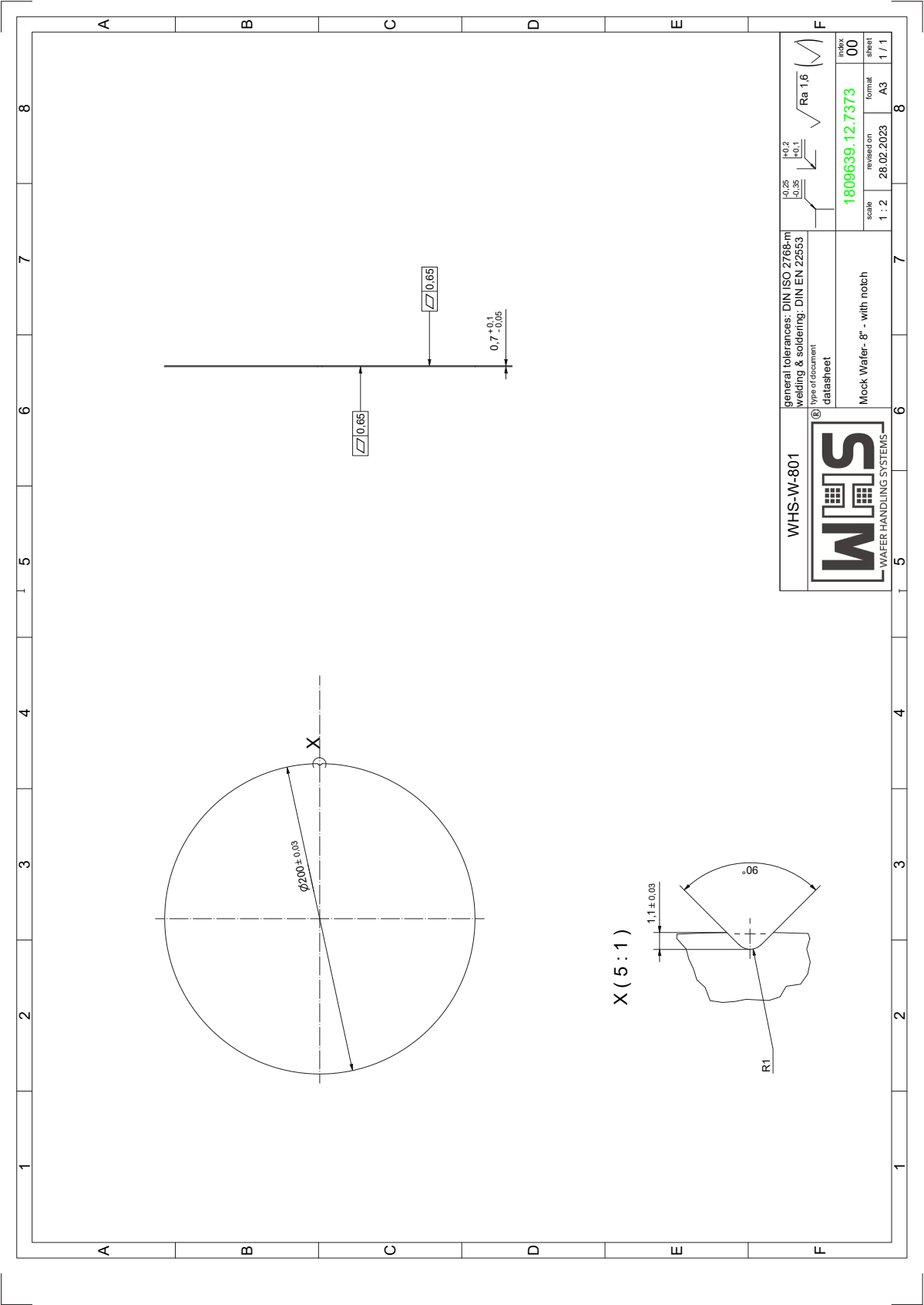
ORDERING INFORMATION

WHS-W-	402
CODE	MODEL
402	Aluminum test wafer, 100 mm (4"), bare, with SEMI flat
602	Aluminum test wafer, 150 mm (6"), bare, with SEMI flat
601	Aluminum test wafer, 150 mm (6"), bare, with SEMI notch.
801	Aluminum test wafer, 200 mm (8"), bare, with SEMI notch.
1201	Aluminum test wafer, 300 mm (12") bare, with SEMI notch.

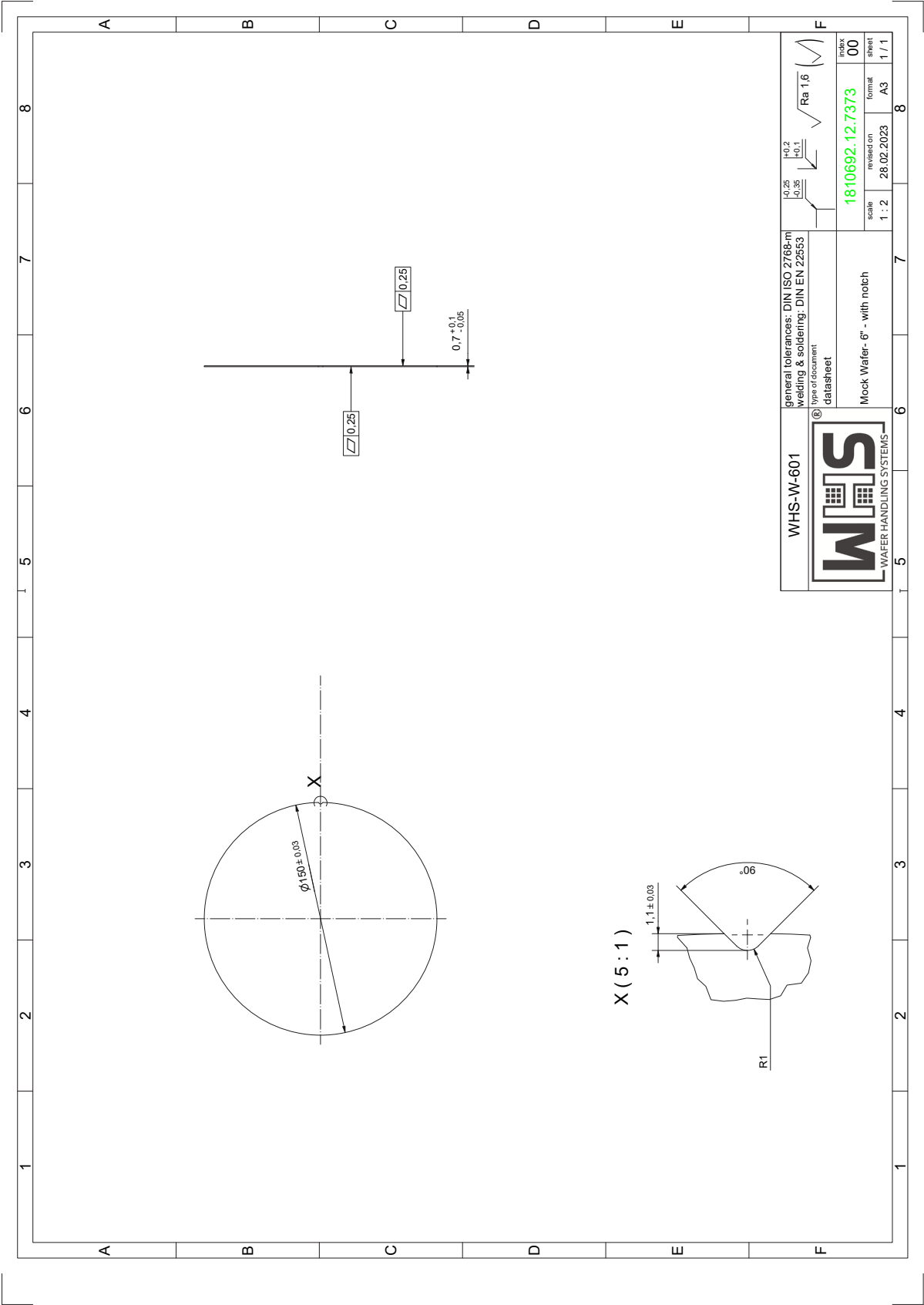
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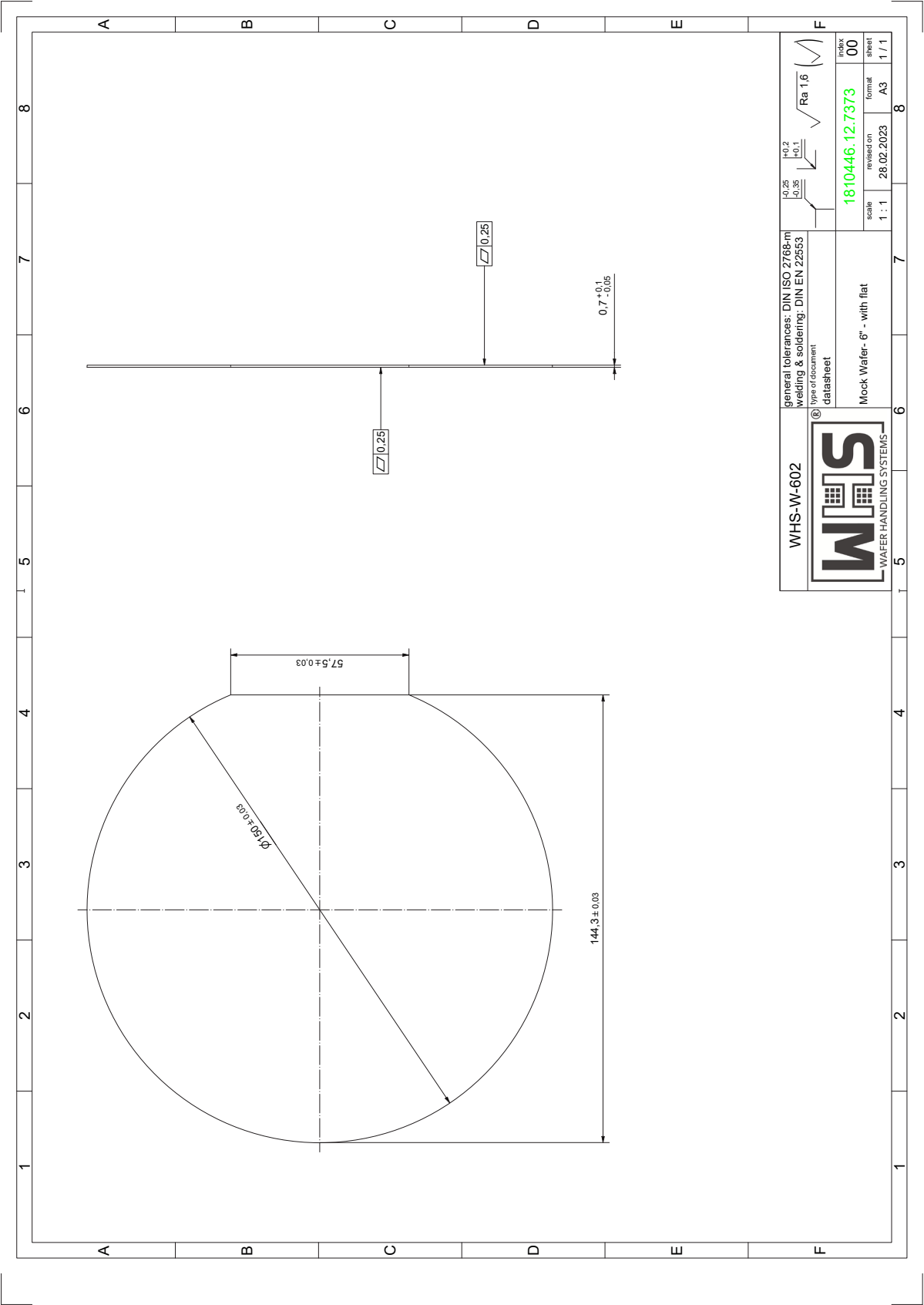
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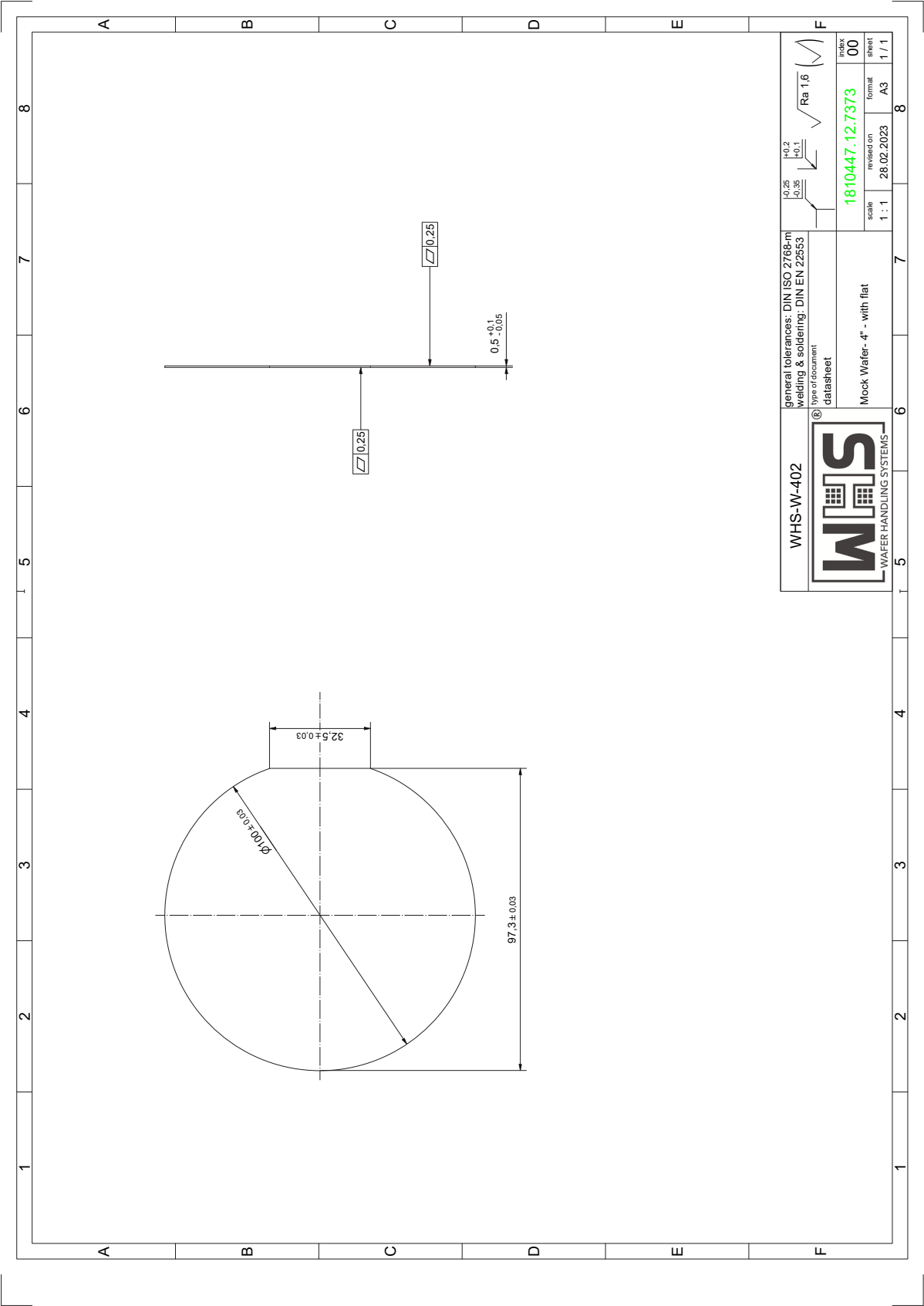




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